## Applicant(s)/Patent Under Application/Control No. Reexamination 10/014,265 **BRUCK ET AL** Notice of References Cited Art Unit Examiner Page 1 of 1 1764 Hien Tran **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY 422/180 10-1995 Machida et al. US-5,455,012 Α 264/109 US-6,080,345 06-2000 Chalasani et al. В US-С US-D Ε US-US-F US-G US-Н US-1 US-J US-Κ US-L US-FOREIGN PATENT DOCUMENTS Date **Document Number** Classification Name Country Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R s Т **NON-PATENT DOCUMENTS** . Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYYY format are publication dates. Classifications may be US or foreign.